

CLASS U.S. PTO

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108-1081

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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10023347	FILING DATE 12/17/2001	CLASS 438	SUBCLASS 401	GAU 2842	EXAMINER Schilling
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**APPLICANTS: Hause Frederick; Haines Jeffrey; Exterkamp Michael;

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**CONTINUING DATA VERIFIED:

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** FOREIGN APPLICATIONS VERIFIED:

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PG-PUB DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	2000.031300
Verified and Acknowledged Examiners's initials <i>Handwritten initials</i>	
TITLE : Method of forming an alignment mark on a wafer, and a wafer comprising same	

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-95)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawg.	Figs. Drawg.
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner PREPARED FOR ISSUE Application Examiner	
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